

Notice of References Cited	Application/Control No. 10/599,482		Applicant(s)/Patent Under Reexamination SHINTANI ET AL.	
	Examiner John P. Sheehan		Art Unit 1793	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0245491	12-2004	Arai et al.	252/062.54
*	B	US-2002/0066498	06-2002	Arai et al.	148/105
*	C	US-6,536,507	03-2003	Arai et al.	164/482
*	D	US-2003/0217788	11-2003	Arai et al.	148/300
*	E	US-2002/0053372	05-2002	Arai et al.	148/300
*	F	US-2002/0028334	03-2002	Arai et al.	428/402
*	G	US-2002/0023697	02-2002	Arai et al.	148/301
*	H	US-5,665,177	09-1997	Fukuno et al.	148/101
*	I	US-7,014,718	03-2006	Hasegawa et al.	148/302
*	J	US-2005/0028892	02-2005	Sasaki, Shiro	148/302
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 02/072900 A2	09-2002	PCT	Ito et al.	-----
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.